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131,072 WORDS × 8 BIT STATIC RAM

DESCRIPTION

The TC551001PL/FL is 1,048,576 bits static random access memory organized as 131,072 words by 8 bits using CMOS technology, and operated a single 5 V power supply. Advanced circuit techniques provide both high speed and low power features with an operating current of 5 mA / MHz (Typ.) and minimum cycle time of 85/100 ns. When $\overline{CE1}$ is a logical high, or CE2 is low, the device is placed in low power standby mode in which standby current is 2 μA typically. The TC551001PL/FL has three control inputs. Chip enable inputs ($\overline{CE1}$,CE2) allow for device selection and data retention control, and an output enable input ($\overline{OE}$) provides fast memory access. Thus the TC551001PL/FL is suitable for use in various microprocessor application system where high speed, low power, and battery back up are required.

The TC551001PL/FL is offered in both a dual-in-line 32 pin standard plastic package and small-out line plastic flat package.

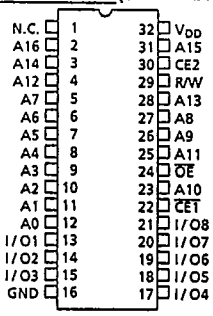
FEATURES

- Low Power Dissipation
  : 27.5 mW/MHz (Typ.)
- Standby Current : 100 μA (Max.)
- 5 V Single Power Supply
- Power Down Feature : $\overline{CE1}$, CE2
- Data retention Supply Voltage : 2.0 ~ 5.5 V
- Directly TTL Compatible
  : All Inputs and Outputs
- Access Time

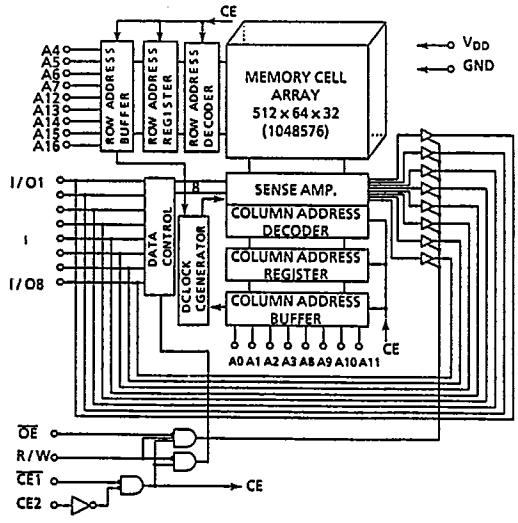
	TC551001 PL/FL-85	TC551001 PL/FL-10
Access Time (max.)	85 ns	100 ns
$\overline{CE1}$ Access Time (max.)	85 ns	100 ns
CE2 Access Time (max.)	85 ns	100 ns
$\overline{OE}$ Access Time (max.)	45 ns	50 ns

- Package : TC551001PL : DIP32-P-600
  TC551001FL : SOP32-P-525

PIN CONNECTION (TOP VIEW)



BLOCK DIAGRAM



PIN NAMES

A0~A16	Address Inputs
R/W	Read/Write Control Input
$\overline{OE}$	Output Enable Input
$\overline{CE1}$,CE2	Chip Enable Input
I/O1~I/O8	Data Input/Output
V_{DD}	Power (+5 V)
GND	Ground
N.C.	No Connection

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OPERATION MODE

OPERATION MODE	$\overline{CE1}$	CE2	$\overline{OE}$	R/W	I/O1 ~ I/O8	POWER
Read	L	H	L	H	D_{OUT}	I_{DDO}
Write	L	H	*	L	D_{IN}	I_{DDO}
Output Deselect	L	H	H	H	High-Z	I_{DDO}
Standby	H	*	*	*	High-Z	I_{DDS}
	*	L	*	*	High-Z	I_{DDS}

* : H or L

ABSOLUTE MAXIMUM RATINGS

SYMBOL	ITEM	RATING	UNIT
V_{DD}	Power Supply Voltage	−0.3 ~ 7.0	V
V_{IN}	Input Voltage	−0.3* ~ 7.0	V
$V_{I/O}$	Input and Output Voltage	−0.5 ~ V_{DD} + 0.5	V
P_D	Power Dissipation	1.0 / 0.6**	W
Tsolder	Soldering Temperature	260 · 10	°C · sec
Tstrg.	Storage Temperature	−55 ~ 150	°C
Topr.	Operating Temperature	0 ~ 70	°C

* : −3.0 V at pulse width 50 ns MAX. ** : SOP

D.C. RECOMMENDED OPERATING CONDITIONS.

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V_{DD}	Power Supply Voltage	4.5	5.0	5.5	V
V_{IH}	Input High Voltage	2.2	−	V_{DD} + 0.3	
V_{IL}	Input Low Voltage	−0.3	−	0.8	
V_{DH}	Data Retention Supply Voltage	2.0	−	5.5	

D.C. and OPERATING CHARACTERISTICS ($Ta = 0 \sim 70\,°C$, $V_{DD} = 5\,V \pm 10\,\%$)

SYMBOL	PARAMETER	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
I_{IL}	Input Leakage Current	$V_{IN} = 0 \sim V_{DD}$	-	-	±1.0	μA
I_{OH}	Output High Current	$V_{OH} = 2.4\,V$	-1.0	-	-	mA
I_{OL}	Output Low Current	$V_{OL} = 0.4\,V$	4.0	-	-	mA
I_{LO}	Output Leakage Current	$\overline{CE1} = V_{IH}$ or $CE2 = V_{IL}$ or $R/W = V_{IL}$ or $\overline{OE} = V_{IH}$, $V_{OUT} = 0 \sim V_{DD}$	-	-	±1.0	μA
I_{DDO1}	Operating Current	$\overline{CE1} = V_{IL}$ and $CE2 = V_{IH}$ and $R/W = V_{IH}$, $I_{OUT} = 0\,mA$, Other Inputs = V_{IH}/V_{IL}, t_{cycle} = Min. cycle	-	-	80	mA
I_{DDO2}		$\overline{CE1} = 0.2\,V$ and $CE2 = V_{DD} - 0.2\,V$, $R/W = V_{DD} - 0.2\,V$, $I_{OUT} = 0\,mA$, Other Inputs = $V_{DD} - 0.2\,V / 0.2\,V$, t_{cycle} = Min. cycle	-	-	70	mA
I_{DDS1}	Standby Current	$\overline{CE1} = V_{IH}$ or $CE2 = V_{IL}$	-	-	3	mA
I_{DDS2} (1)		$\overline{CE1} = V_{DD} - 0.2\,V$ or $CE2 = 0.2\,V$, $V_{DD} = 2.0\,V \sim 5.5\,V$, $Ta = 0 \sim 70\,°C$	-	2	100	μA

Note : (1) In standby mode with $\overline{CE1} \geqq V_{DD} - 0.2\,V$, these specification limits are guaranteed under the condition of $CE2 \geqq V_{DD} - 0.2\,V$ or $CE2 \leqq 0.2\,V$.

CAPACITANCE ($Ta = 25\,°C$, $f = 1\,MHz$)

SYMBOL	PARAMETER	TEST CONDITION	MAX.	UNIT
C_{IN}	Input Capacitance	$V_{IN} = GND$	10	pF
C_{OUT}	Output Capacitance	$V_{OUT} = GND$	10	

Note : This parameter periodically sampled is not 100 % tested.

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A.C. CHARACTERISTICS (Ta = 0 ~ 70 °C, V_{DD} = 5 V ± 10 %)

Read Cycle

SYMBOL	PARAMETER	TC551001PL-85 TC551001FL-85		TC551001PL-10 TC551001FL-10		UNIT
		MIN.	MAX.	MIN.	MAX.	
t_{RC}	Read Cycle Time	85	–	100	–	ns
t_{ACC}	Address Access Time	–	85	–	100	
t_{CO1}	$\overline{CE1}$ Access Time	–	85	–	100	
t_{CO2}	CE2 Access Time	–	85	–	100	
t_{OE}	Output Enable to Output in Valid	–	45	–	50	
t_{COE}	Chip Enable ($\overline{CE1}$, CE2) to Output in Low-Z	10	–	10	–	
t_{OEE}	Output Enable to Output in Low-Z	0	–	0	–	
t_{OD}	Chip Enable ($\overline{CE1}$, CE2) to Output in High-Z	–	30	–	35	
t_{ODO}	Output Enable to Output in High-Z	–	30	–	35	
t_{OH}	Output Data Hold Time	10	–	10	–	

Write Cycle

SYMBOL	PARAMETER	TC551001PL-85 TC551001FL-85		TC551001PL-10 TC551001FL-10		UNIT
		MIN.	MAX.	MIN.	MAX.	
t_{WC}	Write Cycle Time	85	–	100	–	ns
t_{WP}	Write Pulse Width	60	–	60	–	
t_{CW}	Chip Selection to End of Write	75	–	80	–	
t_{AS}	Address Set up Time	0	–	0	–	
t_{WR}	Write Recovery Time	0	–	0	–	
t_{ODW}	R/W to Output in High-Z	–	30	–	35	
t_{OEW}	R/W to Output in Low-Z	0	–	0	–	
t_{DS}	Data Set up Time	35	–	40	–	
t_{DH}	Data Hold Time	0	–	0	–	

A.C. TEST CONDITIONS

Output Load	:	100 pF + 1 TTL Gate
Input Pulse Level	:	0.6 V, 2.4 V
Timing Measurement V_{IN}	:	0.8 V, 2.2 V
Reference Level V_{OUT}	:	0.8 V, 2.2 V
t_r, t_f	:	5 ns

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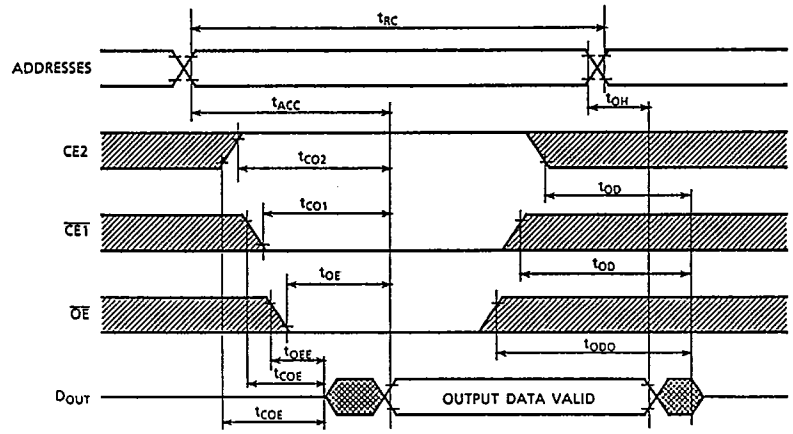
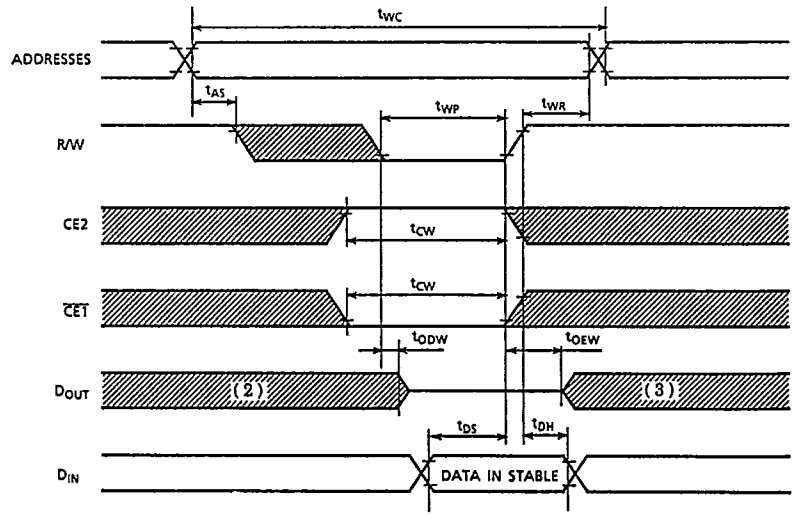
TIMING WAVEFROMS

Read Cycle (1)



Write Cycle 1 (4) (R/W Controlled Write)



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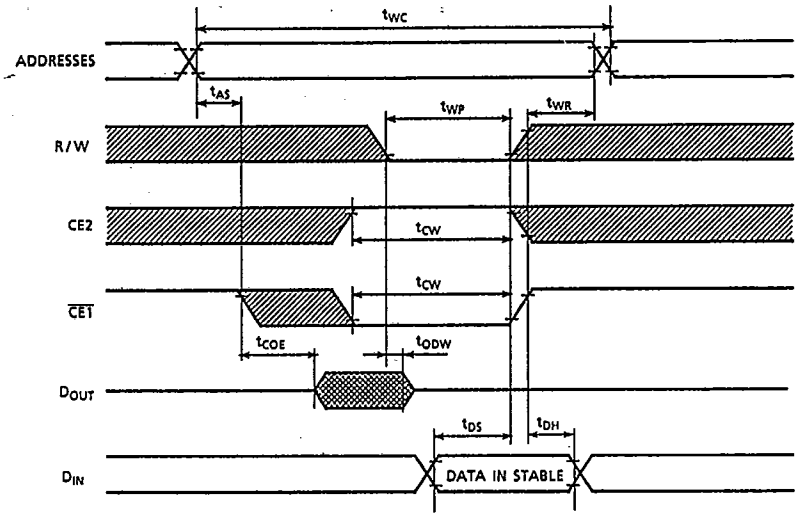
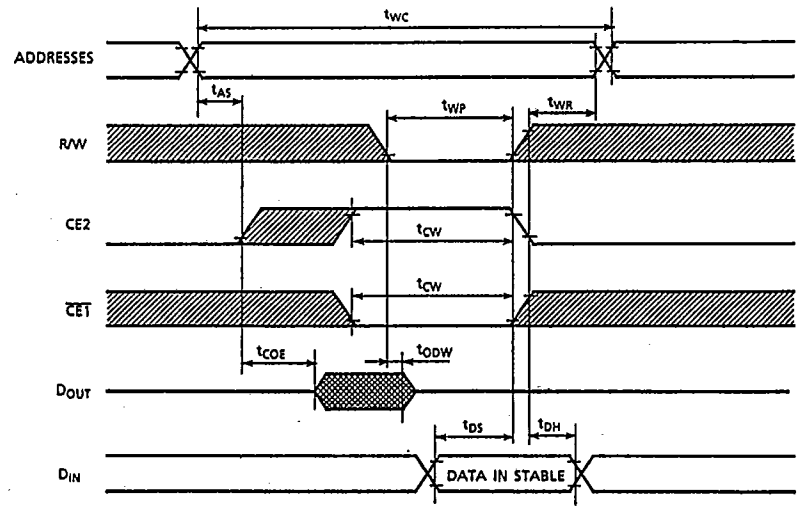
WRITE CYCLE 2 (4) ($\overline{CE1}$ Controlled Write)



WRITE CYCLE 3 (4) (CE2 Controlled Write)



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Note : (1) R/W is High for Read Cycle.

(2) Assuming that $\overline{CE1}$ Low transition or CE2 High transition occurs coincident with or after R/W Low transition, Outputs remain in a high impedance state.

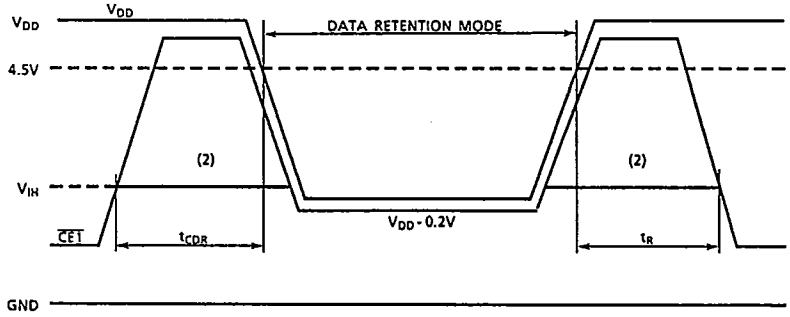
(3) Assuming that $\overline{CE1}$ High transition or CE2 Low transition occurs coincident with or prior to R/W High transition, outputs remain in a high impedance state.

(4) Assuming that $\overline{OE}$ is High for Write Cycle, Outputs are in high impedance state during this period.

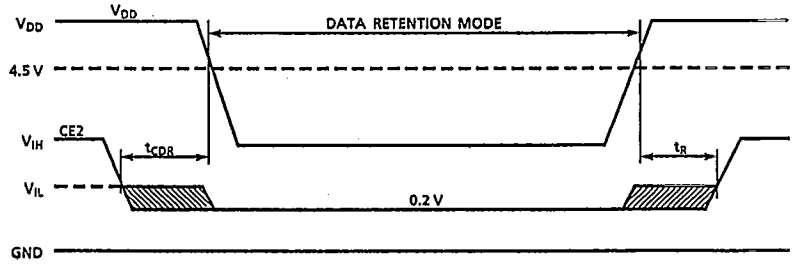
DATA RETENTION CHARACTERISTICS (Ta = 0 ~ 70 °C)

SYMBOL	PARAMETER		MIN.	TYP.	MAX.	UNIT
V_{DH}	Data Retention Supply Voltage		2.0	-	5.5	V
I_{DDS2}	Standby Current	V_{DD} = 3.0 V	-	-	50	μA
		V_{DD} = 5.5 V	-	-	100	
t_{CDR}	Chip Deselection to Data Retention Mode		0	-	-	nS
t_R	Recovery Time		5	-	-	mS

$\overline{CE1}$ Controlled Data Retention Mode (1)



CE2 Controlled Data Retention Mode (3)



Note : (1) In $\overline{CE1}$ controlled data retention mode, minimum standby current mode is achieved under the condition of CE2 ≦ 0.2 V or CE2 ≧ V_{DD} − 0.2 V.

(2) If the V_{IH} of $\overline{CE1}$ is 2.2 V in operation, during the period that the V_{DD} voltage is going down from 4.5V to 2.4 V, I_{DDS1} current flows.

(3) In CE2 controlled data retention mode, minimum standby current mode is achieved under the condition of CE2 ≦ 0.2 V.

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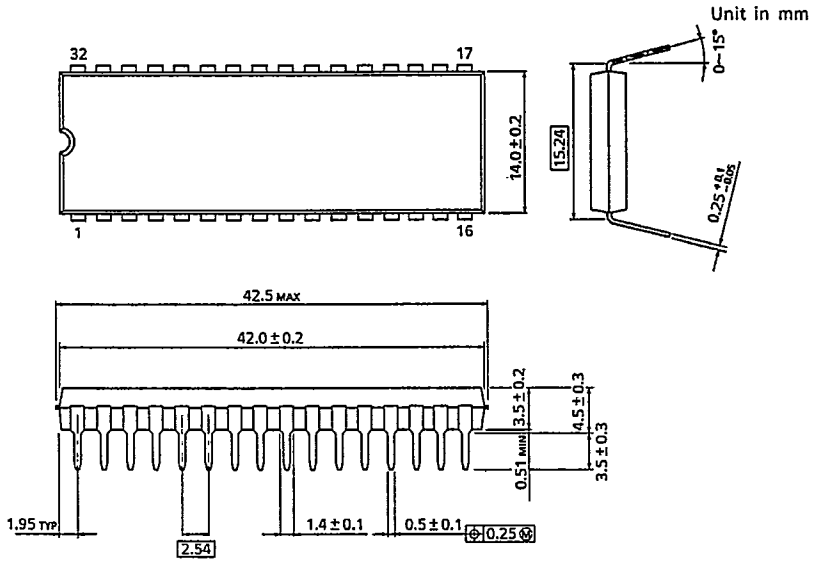
OUTLINE DRAWING (DIP32 – P – 600)

Unit in mm



Weight : 4.53g (Typ.)

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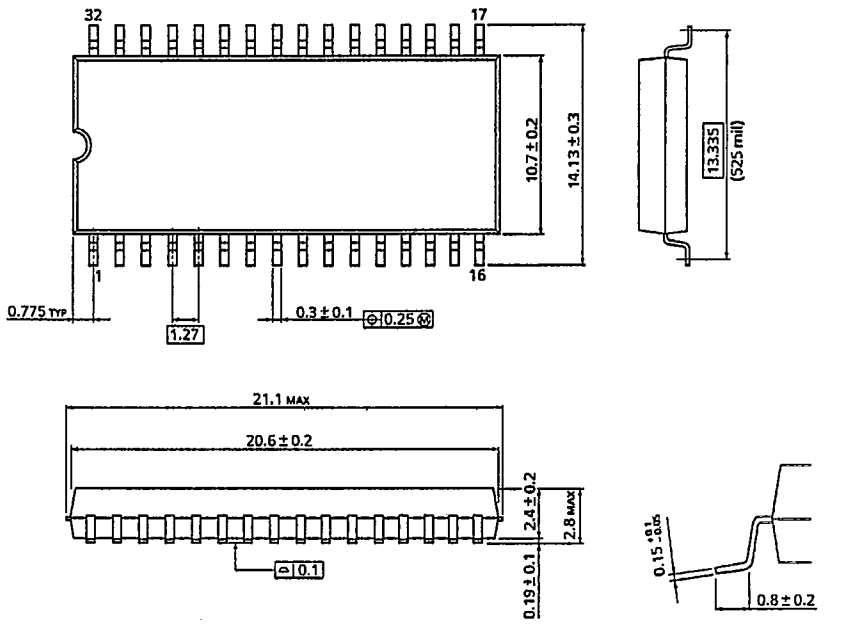
OUTLINE DRAWING (SOP32-P-525)

Unit in mm



Weight : 1.10g (Typ.)